A spin eld e ect transistor for low leakage current

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A bstract

In a spin eld e ect transistor, a magnetic eld is inevitably present in the channel because of the ferrom agnetic source and drain contacts. This eld causes random unwanted spin precession when carriers interact with non-magnetic in purities. The random ized spins lead to a large leakage current when the transistor is in the \circ "-state, resulting in signi cant standby power dissipation. We can counter this e ect of the magnetic eld by engineering the D resselhaus spin-orbit interaction in the channel with a backgate. For realistic device parameters, a nearly perfect cancellation is possible, which should result in a low leakage current.

Keywords: Spintronics, Spin eld e ect transistors, spin orbit interaction PACS: 85.75 Hh, 72.25 D c, 71.70 E j

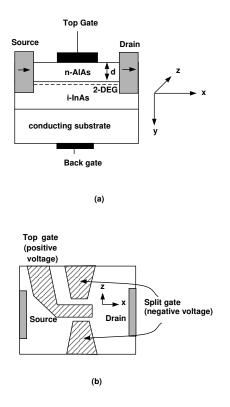


Fig. 1. A spin eld e ect device with a one-dimensional channel. (a) side view showing a top gate for modulating the spin precession via the Rashba interaction and a back gate for modulating the channel carrier concentration. The substrate will be p^+ if we want to deplete the channel with the back-gate, and n^+ if we want to accumulate it. (b) top view showing the split gate con guration required to produce a one-dimensional channel, as well as the top gate. A positive voltage is applied to the top gate to increase the interface electric eld that modulates the Rashba interaction and produces the conductance modulation, whereas a negative voltage is applied to the split gates to constrict the one-dimensional channel.

M uch of the current interest in spintronic transistors is motivated by a wellknown device proposal due to D atta and D as [1] that has now come to be known as a Spin Field E ect Transistor (SPINFET). This device consists of a one-dimensional sem iconductor channel with half-metallic ferrom agnetic source and drain contacts that are magnetized along the channel (Fig. 1). Electrons are injected from the source with their spins polarized along the channel's axis. The spin is then controllably precessed in the channel with a gate voltage that modulates the Rashba spin-orbit interaction [2]. At the drain end, the transmission probability of the electron depends on the component of its spin vector along the channel. By controlling the angle of spin precession in the channel with a gate voltage, one can control this component, and hence control the source-to-drain current. This realizes the basic \transistor" action [3]. In their original proposal [1], D atta and D as ignored two e ects: (i) the m agnetic eld that is inevitably present in the channel because of the ferrom agnetic source and drain contacts, and (ii) the D resselhaus spin orbit interaction [4] arising from bulk (crystallographic) inversion asymmetry. In the past, we analyzed the e ect of the channel magnetic eld and showed that it could cause weak spin ip scattering via interaction with non-magnetic elastic scatterers [5]. The ipped spins, whose precession angles have been random ized by the spin ip scattering events, will lead to a large leakage current when the device is in the \o "-state. This is a serious drawback since it will lead to an unacceptable standby power dissipation in a circuit com posed of Spin Field E ect Transistors. In order to elim inate the leakage current, we must elim inate the unwanted spin ip scattering processes. In other words, we must nd ways to counter the deleterious e ect of the channel magnetic eld. The purpose of this paper is to explore how this can be achieved.

In a strictly one-dimensional structure, where transport in single channeled, there is no D'yakonov-Perel spin relaxation [6]. Therefore, the only agents that can cause spin random ization are hyper ne interactions with the nuclei and spin mixing e ects caused by the channel magnetic eld [5]. In order to elim inate the latter (which is the stronger of the two agents), we can adopt one of two options: either elim inate the magnetic eld by using non-magnetic spin-injector (source contact) and detector (drain contact) [7], or counteract the e ect of the magnetic eld with some other e ect. The form er approach presents a form idable engineering challenge. The latter can be implemented more easily, and, as we show in this paper, is achieved by countering the e ect of the magnetic eld with the D resselhaus interaction. Calculations based on realistic parameters for InA s transistor channels show that this is indeed possible.

C onsider the one-dimensional channel of the device in Fig. 1. Because of the magnetized source and drain contacts, a magnetic eld exists along the wire in the x-direction. We will assume that the channel (x-direction) is along the [100] crystallographic axis.

The elective mass Hamiltonian for the wire, in the Landau gauge A = (0, Bz, 0), can be written as

$$H = (p_x^2 + p_y^2 + p_z^2) = (2m) + (eB z p_y) = m + (e^2 B^2 z^2) = (2m) \quad (g=2) B x + V (y) + V (z) + 2a_{42} [x + y + y + z] + [(p_x=-) z (p_z=-) x]$$

where g is the Lande g-factor, $_{\rm B}$ is the Bohr m agneton, V (y) and V (z) are the con ning potentials along the y- and z-directions, -s are the Pauli spin m atrices, $2a_{42}$ is the strength of the D resselhaus spin-orbit interaction (a_{42} is a m aterial parameter) and is the strength of the R ashba spin-orbit interaction. The quantities are de ned in ref. [8].We will assume that the wire is narrow enough and the temperature is low enough that only the lowest magnetoelectric subband is occupied. Since the Ham iltonian is invariant in the xcoordinate, the wavevector k_x is a good quantum number and the eigenstates are plane waves traveling in the x-direction. A coordingly, the spin Ham iltonian (spatial operators are replaced by their expected values) simpli es to

$$H = (\sim^{2} k_{x}^{2}) = (2m) + E_{0} + (k_{x})_{x} + k_{x}_{z}$$
(2)

where E₀ is the energy of the low est m agneto-electric subband, (B) = $2a_{42} \\ k_y^2 > < k_z^2 > + (e^2 B^2 < z^2 > =\sim^2)$], (z) is the z-com ponent of the wave-function, (y) is the y-com ponent of the wavefunction, < $k_y^2 > = (1=\sim^2) < (y)j$ ($e^2 = e^2 y^2$)j (y) >, < $k_z^2 > = (1=\sim^2) < (z)j$ ($e^2 = e^2 y^2$)j (z) >, and = (g=2) B B.

Since the potential V (z) is parabolic (V (z) = $(1=2)m \ !_0^2 z^2$), it is easy to show that $\langle k_z^2 \rangle = m \ !=(2\sim)$ and $\langle z^2 \rangle = \sim =(2m \ !)$ where $!^2 = !_0^2 + !_c^2$ and $!_c$ is the cyclotron frequency ($!_c = eB = m$). Furthermore, $E_0 = (1=2)\sim ! + E$ where E is the energy of the lowest subband in the triangular well V (y).

D isoponalizing this H am iltonian in a truncated H ilbert space spanning the two spin resolved states in the lowest subband yields the eigenenergies [9]

and the corresponding eigenstates

$${}_{+} (B;x) = \begin{cases} 2 & 3 \\ 6 & \cos(k_{x}) & 7 \\ 5 & \sin(k_{x}) \\ \sin(k_{x}) \end{cases} (B;x) = \begin{cases} 2 & 3 \\ 6 & \sin(k_{x}) & 7 \\ 6 & \cos(k_{x}) \\ \cos(k_{x}) \end{cases} (4)$$

where $k_x = (1=2) \arctan [(k_x) = k_x]$.

The dispersion relations given by Equation (3) can be found plotted in ref. [9]. The dispersions are clearly nonparabolic and could be asymmetric about the energy axis. More importantly, note that the eigenspinors given in Equation (4) are functions of k_x because k_x depends on k_x . Therefore, the eigenspinors are not xed in any subband, but change with k_x . In other words, neither subband has a denite spin quantization axis and the orientation of the spin vector of an electron in either subband depends on the wavevector. Consequently, it is always possible to not two states in the two subbands with non-orthogonal spins. Any non-magnetic scatterer (impurity, phonon, etc.) can then couple these two states and cause a spin-relaxing scattering event. It is this spin ip

process that leads to a non-zero o -conductance (and leakage current) and needs to be eliminated.

It is easy to see that the way to eliminate the spin ip process is to enforce the condition:

$$k_x =$$
 (5)

In this case, the dispersion relations become

$$E = E_0 \frac{2}{2m}k_R^2 + \frac{2}{2m}(k_x - k_R)^2$$
(6)

where $k_R = m = -2^{2}$, and the eigenstates become

$${}_{+}(\mathbf{x}) = {\begin{array}{*{20}c} 2 & 3 \\ 6 & {}^{1} & {}^{7}_{5} & {\rm e}^{{\rm i} k_{x} x} \\ 0 & & & & \\ 0 & & & & \\ 1 & & & \\ \end{array}}$$

$${\begin{array}{*{20}c} 2 & 3 \\ 0 & {}^{7}_{5} & {\rm e}^{{\rm i} k_{x} x} \\ 1 & & & \\ \end{array}}$$

$$(7)$$

The dispersion relation in Equation (6) is parabolic (two parabolas displaced horizontally from the origin by k_R) and each has a denite (wavevector-independent) spin quantization axis which is + z-polarized in the rst subband and -z-polarized in the second subband. Since the two subbands have orthogonal spin polarizations at any wavevector, no non-m agnetic scatter can couple them and cause a spin ip event. Therefore, we can successfully eliminate the unwanted spin ip processes when we enforce the condition in Equation (5).

Equations (6) and (7) are the dispersions and eigenstates employed in ref. [1]. They are correct only if we counteract the channel magnetic eld with the D resselhaus interaction as embodied by the condition in Equation (5).

We now proceed to estimate realistic values of and to see if the condition in Equation (5) can be realized. This equation can be recast as

$$2a_{42} < k_y^2 > \frac{m!}{2\sim} + \frac{e^2 B^2}{2m \sim !} k_F = \frac{g_B B}{2}$$
 (8)

where we have assumed that $k_{\rm x}$ = $\,k_{\rm F}$, the Ferm iwavevector.

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W e w ill assume a 0.2 m long channel where the magnetic eld can be as large as 1 Tesla [10,11]. Table 1 lists the parameters used for various quantities used in Equation (8) (along with the citations for the sources when appropriate). U sing these parameters, we not that in order to counter a magnetic eld of 1 Tesla through the D resselhaus interaction, we need $k_F = 2.47 \quad 10^9 \text{ m}^{-1}$, which corresponds to a linear carrier concentration n_1 of 1.54 $\quad 10^9 \text{ m}^{-1}$. A larger magnetic eld would require a larger Ferm i wavevector and a larger carrier concentration.

Table 1 Param eters for a InAs spin interferom eter

a ₄₂	1.6 10 ²⁹ eV-m ³ [15]
g	14.4 [16]
~! ₀	10 m eV [17]
m	0.034 9.1 10 ³¹ Kg
< k _y ² >	10 ¹⁶ m ¹

The purpose of the backgate in Fig. 1 now becomes clear. We can tune the carrier concentration and Ferm is avevector $k_{\rm F}$ in the channel to the optimum value with a backgate voltage. The top gate can then be used exclusively to modulate the Rashba interaction which leads to conductance modulation of the transistor. As we swing the top gate voltage to switch the transistor from <code>\on"</code> to <code>\o"</code>, or vice versa, this gate voltage swing $V_{\rm G}$ will also induce some unavoidable uctuation in $k_{\rm F}$. We need to ensure that this uctuation $k_{\rm F}$ is a small percentage of $k_{\rm F}$, so that the act of switching the device does not nullify the balance between the Zeem an splitting (magnetic eld) and the D resselhaus interaction.

In ref. [12], we found that V_G required to induce a spin precession of radians in an ideal 0.2 m long InAs SPINFET channel is about 50 mV if the gate insulator thickness d (see Fig. 1) is 20 nm [13]. This is the voltage swing required to switch such a SPINFET from \on" to \o", or vice versa. U sing standard m etal oxide sem iconductor eld e ect device theory, the change in the (two-dimensional) carrier concentration N_S induced by a gate voltage swing V_G is given by

$$e N_{s} = (=d) V_{G}$$
 (9)

A ssum ing that the gate insulator is A IA s, for which = 8.9 times the permittivity of free space [14] and d = 20 nm, we nd that for V_G = 50 mV, N_s = 1.375 10^{15} m⁻². The corresponding uctuation in the linear carrier concentration is found by multiplying this quantity with the elective width W_{eff} of the InAs channel which is ~=(2m !). For ~! = 10 meV, W_{eff} = 22 nm. Therefore the uctuation in the linear carrier concentration n₁, sustained during switching the SPINFET from \on" to \o", or vice versa, is about 3 $10^7 \ m^{-1}$. This is only 2% of n_1 . Therefore, the modulation of the top gate voltage, during switching, does not a ect the channel carrier concentration (or k_F) signi cantly. A coordingly, it does not seriously a ect the balance between the magnetic eld and the D resselhaus interaction.

0.0.0.1 W hich way should the contacts be magnetized? Before concluding this paper, we bring out an important issue. It is obvious by looking at Equations (3) and (4) that the dispersion relations and the eigenspinors depend not only on the magnitude but also the sign of . Therefore, the \cancellation e ect" discussed in this paper and embodied in Equation (8) is possible only if the magnetization of the contacts is directed in a certain way. For example, if the left hand side of Equation (8) is positive, then the contacts should be magnetized along the direction of current ow provided the g-factor is positive. If the g-factor is negative, then the contacts should be magnetized against the direction of current ow . The exact opposite is true if the left hand side of Equation (8) is negative. To our know ledge, no work on the Spin Field E ect Transistor has ever addressed the issue of which way the contacts should be magnetized. Here we show, for the rst time, that this matter is in portant.

In conclusion, we have shown how the deleterious e ect of the channel m agnetic eld in a Spin Field E ect Transistor can be countered with the D resselhaus interaction. In deriving this result, we have also shown that for the cancellation to happen, there is an optimum channel carrier concentration n_1 that depends on the connem ent energy ~! in the channel, the channel m agnetic eld, the strength of the D resselhaus interaction a_{42} , the e ective m ass and Lande g-factor of the channel m aterial, and the degree of connem ent of the two-dimensional electron gas at the heterointerface represented by the quantity $< k_y^2 >$. Since norm ally m any of these parameters will be unknown in any given sample, it will be necessary to vary the carrier concentration in the channel with a backgate till optimum performance is achieved. To our know hedge, no experimental attempt at demonstrating this device has considered using a backgate to improve performance. This may how ever be an important consideration.

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